

## Supporting Information

**In-situ sulfidation of porous sponge-like CuO/SiW<sub>11</sub>Co into Cu<sub>2</sub>S/SiW<sub>11</sub>Co as stabilized and efficient counter electrode for quantum dot-sensitized solar cells**

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## 1. Experimental section

### 1.1 Chemicals and materials

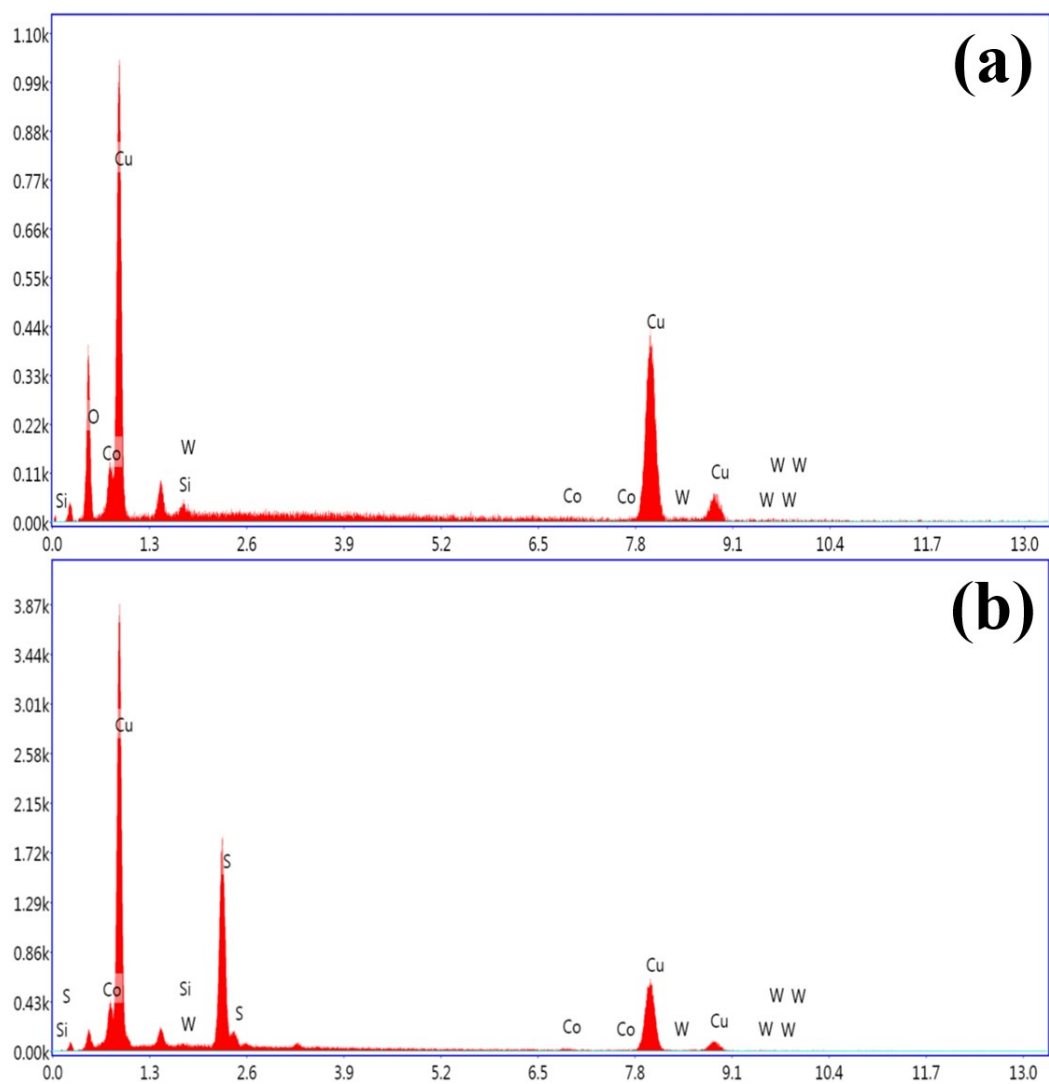
$\text{Cu}(\text{NO}_3)_2 \cdot 3\text{H}_2\text{O}$  (AR,  $\geq 99.5\%$ ),  $(\text{NH}_2)_2\text{CO}$  (AR,  $\geq 99.0\%$ ),  $\text{H}_4\text{SiW}_{12}\text{O}_{40} \cdot x\text{H}_2\text{O}$  (AR,  $\geq 99.5\%$ ),  $\text{C}_4\text{H}_6\text{CuO}_4 \cdot \text{H}_2\text{O}$  (AR,  $\geq 98.0\%$ ), Terpineol ( $\text{C}_{10}\text{H}_{18}\text{O}$ , AR),  $\text{NH}_4\text{Cl}$  (AR,  $\geq 99.0\%$ ),  $\text{H}_2\text{NCSNH}_2$  (AR,  $\geq 99.0\%$ ),  $\text{C}_4\text{H}_6\text{O}_4\text{Zn} \cdot 2\text{H}_2\text{O}$  (AR,  $\geq 99.0\%$ ),  $\text{KCl}$  (AR,  $\geq 99.5\%$ ),  $\text{Na}_2\text{SO}_3$  (AR,  $\geq 97.0\%$ ), absolute methanol and acetone were purchased from Sinopharm.  $\text{Na}_2\text{S} \cdot 9\text{H}_2\text{O}$  (AR,  $\geq 98.0\%$ ), Sulfur (S, 99.99%), Titanium oxide ( $\text{TiO}_2$ , Degussa, P25),  $\text{CdCl}_2$  (AR,  $\geq 99.0\%$ ),  $\text{CdSO}_4$  (AR, 99.0%),  $\text{N}(\text{CH}_2\text{COONa})_3$  (AR, 98.0%), selenium powder (Se, 200 mesh, 99.9%) were purchased from Shanghai Aladdin Biochemical Technology Co., Ltd.

### 1.2 Synthesis of $\text{SiW}_{11}\text{Co}$

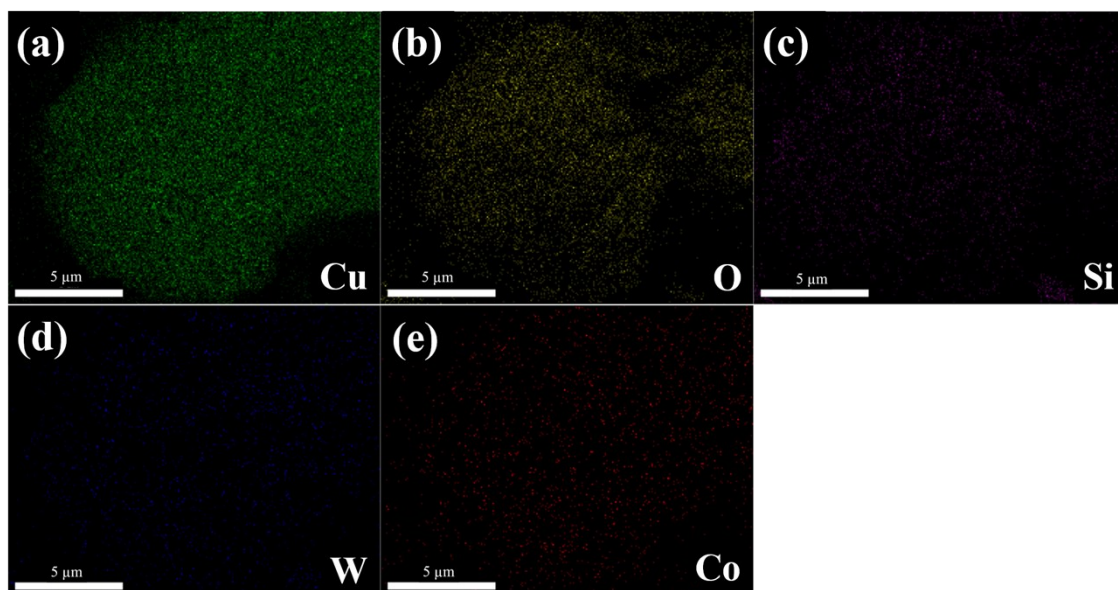
$\text{H}_4\text{SiW}_{12}\text{O}_{40} \cdot x\text{H}_2\text{O}$  ( $\text{SiW}_{12}$ ) (2 mmol) is dissolved in a certain amount of water, and heating to  $85^\circ\text{C}$ . Take an appropriate amount of cobalt acetate solution, adding it dropwise to the above solution and continually heating 20 min at  $85^\circ\text{C}$ . After cooling to room temperature, add acetone to the obtained precipitate, dissolving and filtering the solution. Then continue to add acetone until no precipitation occurs. Finally, evaporate the acetone at  $65^\circ\text{C}$  and dry it at  $50^\circ\text{C}$  for 10h to obtain the product.

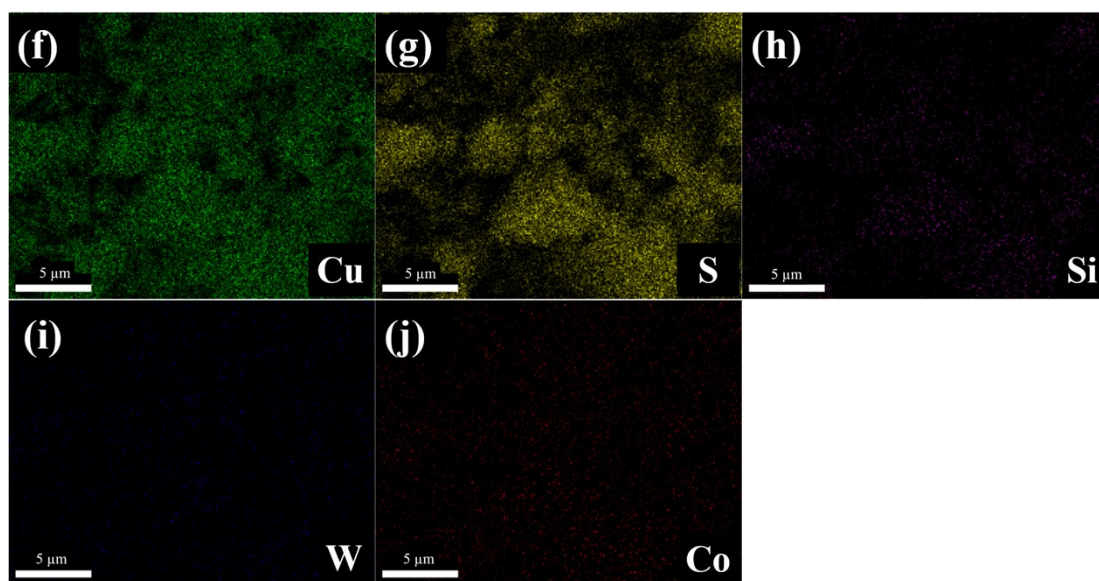
## 2. Characterizations

X-ray powder diffraction test was conducted from  $15$  to  $80^\circ$  adopting Siemens D5005 diffractometer with Cu target  $\text{K}\alpha$  ( $\lambda = 1.5418 \text{ \AA}$ ) rays as X-ray source. A field emission scanning electron microscope (SEM JEOL JSM 4800F) equipped with X-ray energy dispersion (EDX) analysis was used to study the surface morphology and element composition of the samples. X-ray photoelectron spectroscopy (XPS) was carried out applying an ESCALABMKII spectrometer and the X-ray source was achromatic Al-K $\alpha$  (1486.6 eV). The electron transmission microscopy (TEM) and HRTEM images was received using the transmission electron microscope JEOL-2100F. The datas of nitrogen adsorption–desorption isotherms were collected from an ASAP 2020 (Micromeritics, USA). An IVIUM purchased from Tianjin Brillante Technology Limited with a filtered 500 W Xenon lamp is utilized to current–voltage (I–V) curves measurements under the condition of AM 1.5  $100 \text{ mW cm}^{-2}$ . The EIS, Tafel, CV and open circuit voltage decay (OCVD) tests are all used CHI660D electrochemical workstation (Shanghai Chenhua, China). EIS test conditions: the frequency range is  $10^{-1}$ – $10^5 \text{ Hz}$ ; the amplitude is 0.01 V, which is performed under the condition of open-circuit voltage. All characterizations were conducted at ambient temperature and pressure.

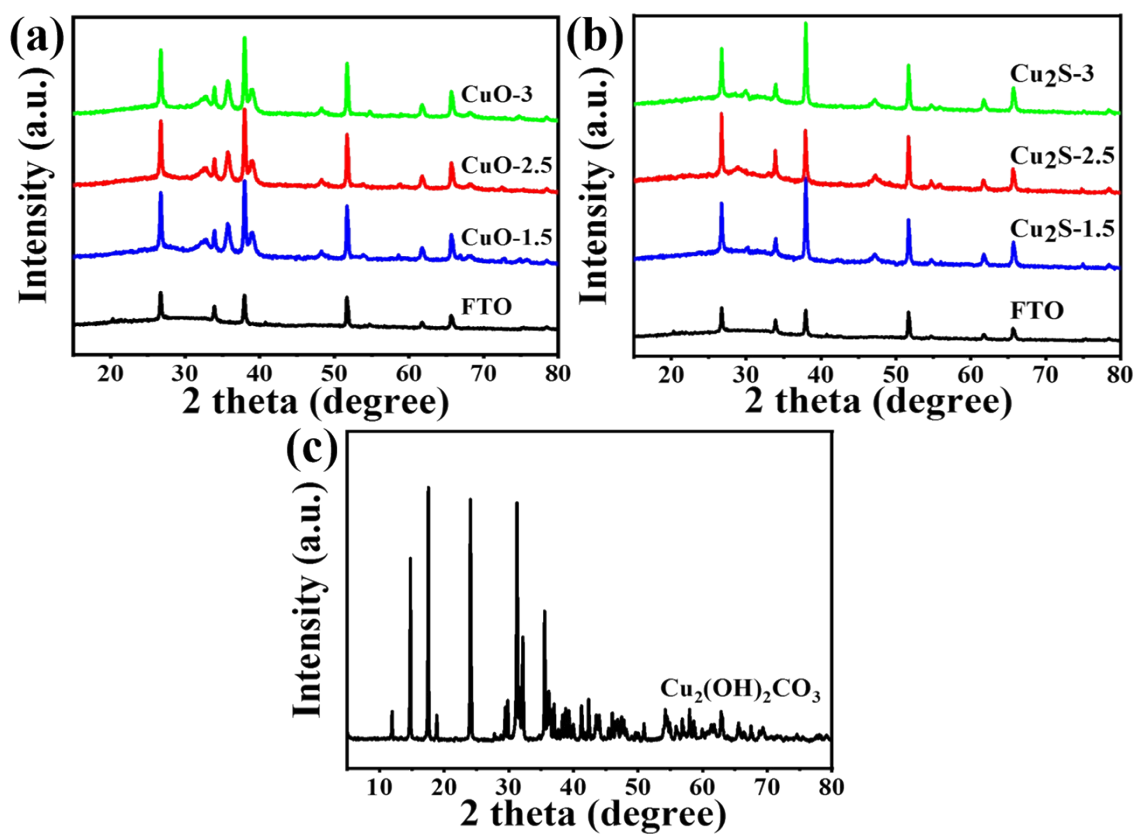


**Fig. S1.** EDX images of (a) CuO-2 and (b) Cu<sub>2</sub>S-2





**Fig. S2.** (a-e) EDX elemental mappings of (a) Cu, (b) O, (c) Si, (d) W, (e) Co in as-prepared CuO-2 sample. (f-j) EDX elemental mappings of (f) Cu, (g) S, (h) Si, (i) W, (j) Co in Cu<sub>2</sub>S-2 sample.



**Fig. S3.** XRD patterns of (a) CuO, (b) Cu<sub>2</sub>S with different SiW<sub>11</sub>Co doping ratio. (c) XRD of Cu<sub>2</sub>(OH)<sub>2</sub>CO<sub>3</sub> precursor.

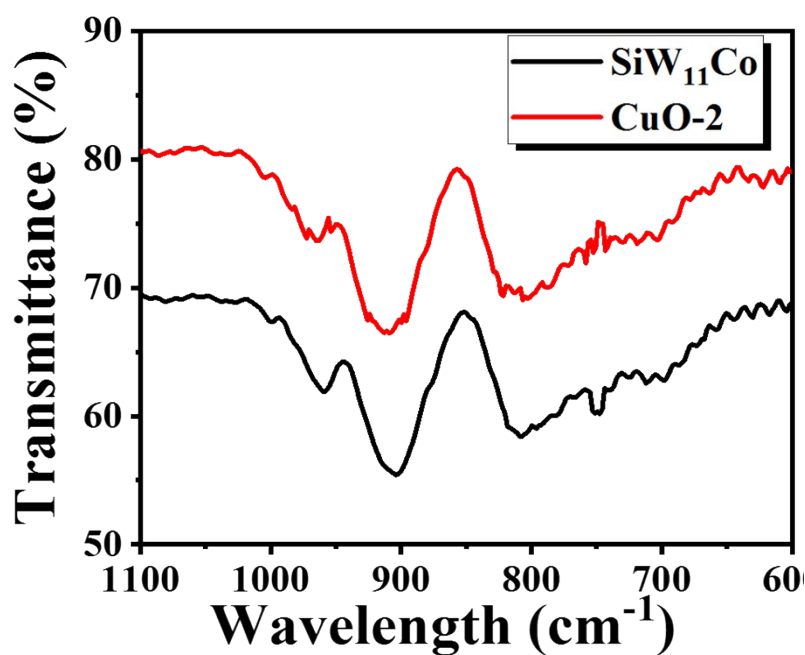


Fig. S4. IR spectrogram of SiW<sub>11</sub>Co and CuO-2 product.

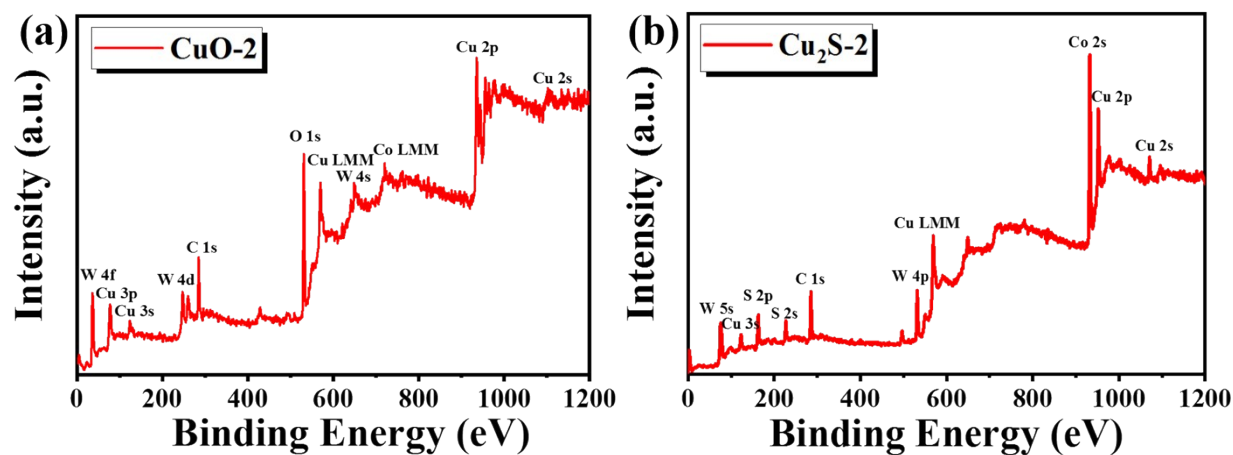


Fig. S5. XPS survey spectrum of (a) CuO-2 and (b) Cu<sub>2</sub>S-2.

Table S1. Detailed BET datas for different samples.

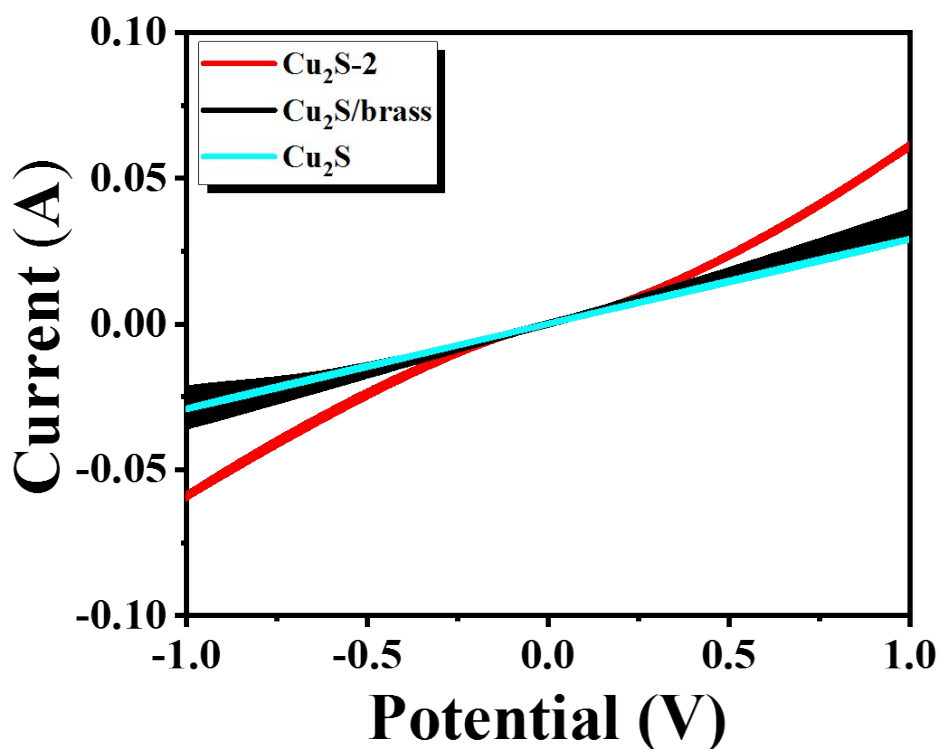
Sample	S <sub>BET</sub> (m <sup>2</sup> /g)	Pore volume (cm <sup>3</sup> /g)	Pore width (nm)
CuO	40.38	0.19	17.52
CuO-2	54.78	0.22	17.46

**Table S2.** Performances parameters of QDSSCs assembled with different CEs.

Counter electrode	$J_{sc}$ (mA/cm <sup>2</sup> )	$V_{oc}$ (V)	FF	PCE (%)
<b>Cu<sub>2</sub>S-2.5</b>	21.42	0.53	0.49	5.71
<b>Cu<sub>2</sub>S-1.5</b>	21.50	0.52	0.48	5.42
<b>Cu<sub>2</sub>S-3</b>	20.00	0.53	0.46	5.04

**Table S3.** Electrochemical parameters of different counter electrodes films.

Counter electrode	$R_s$ ( $\Omega$ )	$R_{ct}$ ( $\Omega$ )	$J_0$ (mA/cm <sup>2</sup> )	$\tau_e$ (ms)
<b>Cu<sub>2</sub>S-2.5</b>	2.210	0.276	2.22	43.91
<b>Cu<sub>2</sub>S-1.5</b>	2.364	0.282	1.60	36.69
<b>Cu<sub>2</sub>S-3</b>	2.489	0.293	1.59	32.60

**Fig. S6.** 10 cycles of CV plots of the symmetrical dummy cells with various CEs in the dark.

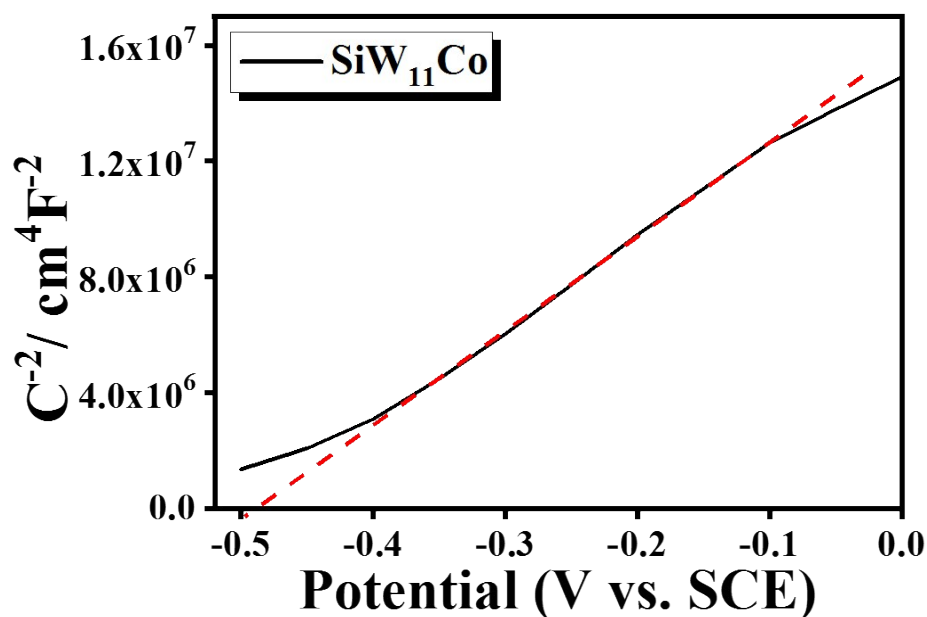


Fig. S7. Mott-Schottky curve of SiW<sub>11</sub>Co.

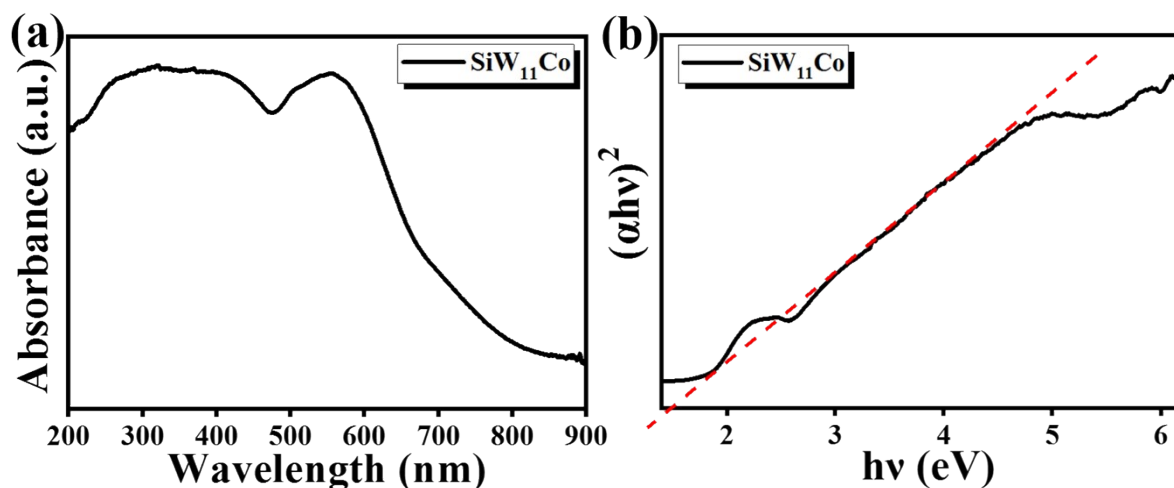
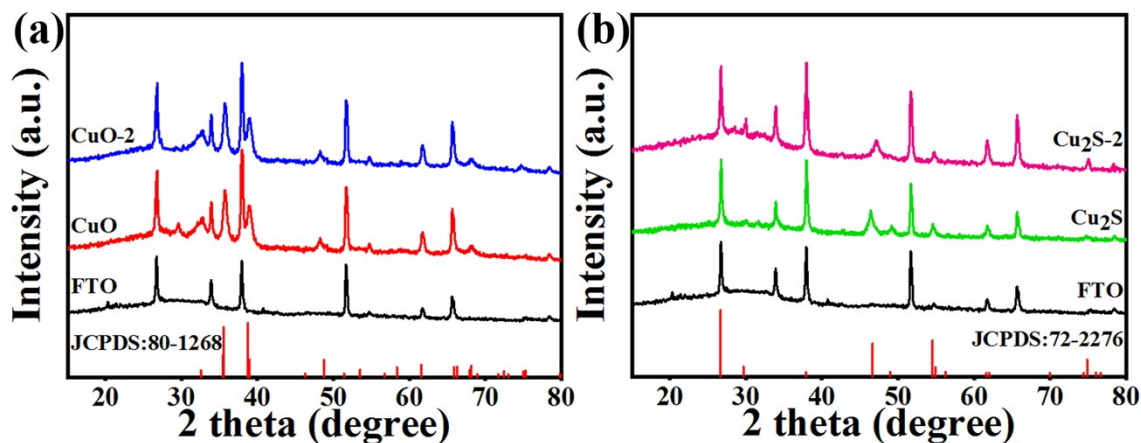


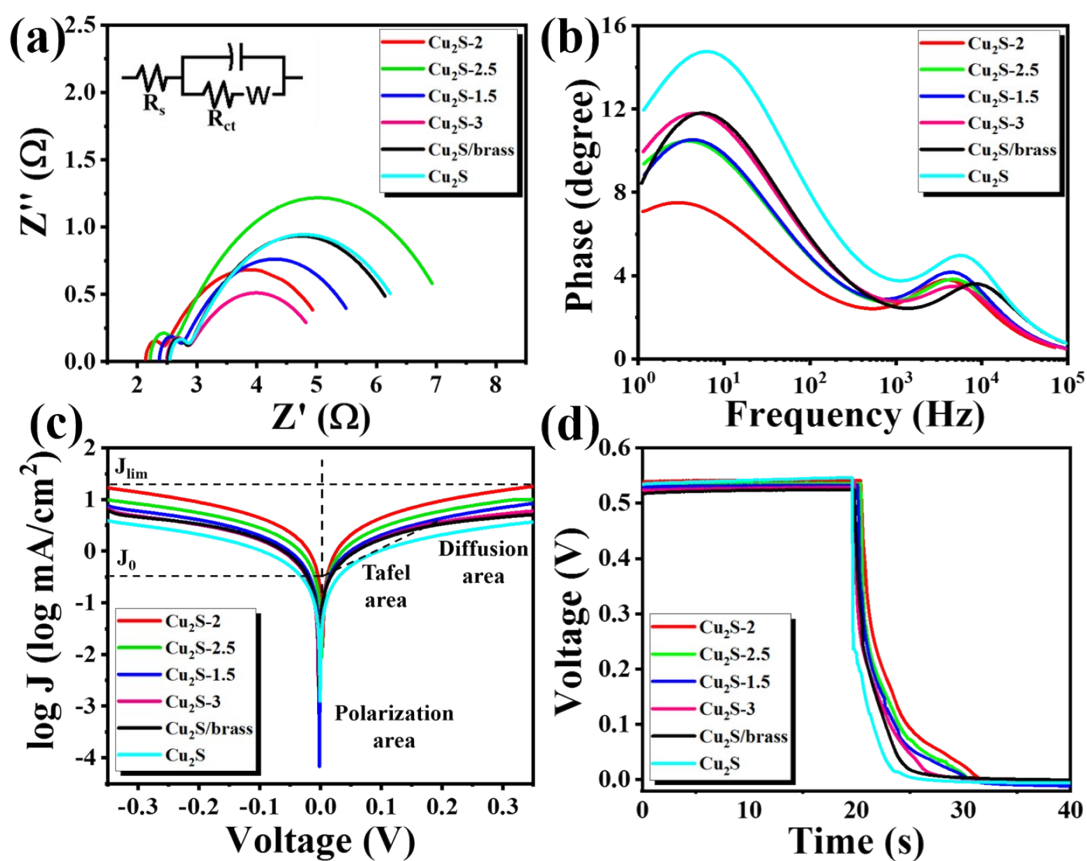
Fig. S8. UV-visible diffuse reflectance spectrum (a) and the band gap calculation (b) of SiW<sub>11</sub>Co.

#### Method of obtaining SiW<sub>11</sub>Co CB or VB:

As can be obtained from Fig. S7, the value of SiW<sub>11</sub>Co  $E_{CB}$  is -0.491 V (vs. SCE). According to the formula of  $E_{RHE} = E_{SCE} + 0.241$  (ref. Applied Catalysis A: General 2017, 536, 67.),  $E_{CB} = -0.25$  V (vs. NHE, -4.25 V vs. AVS). Besides, from the band gap spectra in Fig. S8, we can calculate the  $E_g$  of SiW<sub>11</sub>Co is 1.51 eV, on the basis of  $E_g = E_{CB} - E_{VB}$ , the  $E_{VB}$  of SiW<sub>11</sub>Co is +1.26 V (vs. NHE, -5.76 V vs AVS).

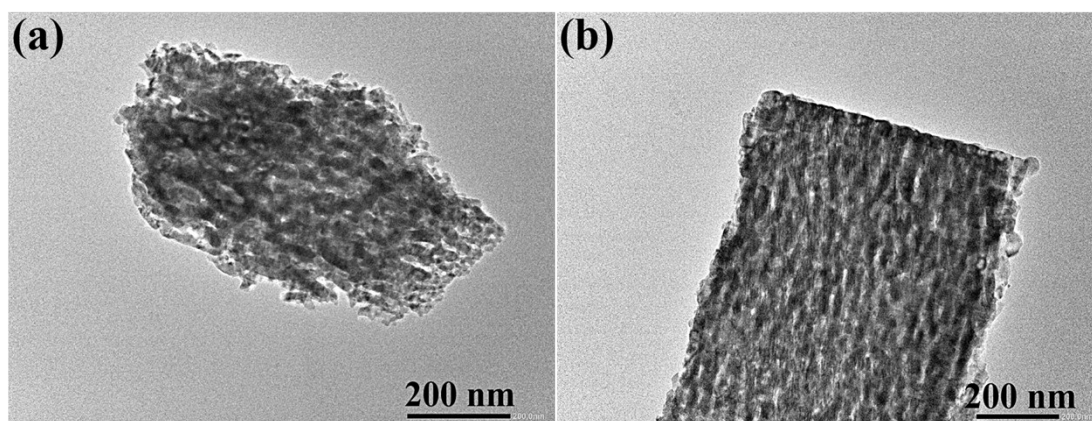


**Fig. S9.** XRD patterns of (a) CuO, CuO-2, (b) Cu<sub>2</sub>S, Cu<sub>2</sub>S-2 films on FTO.

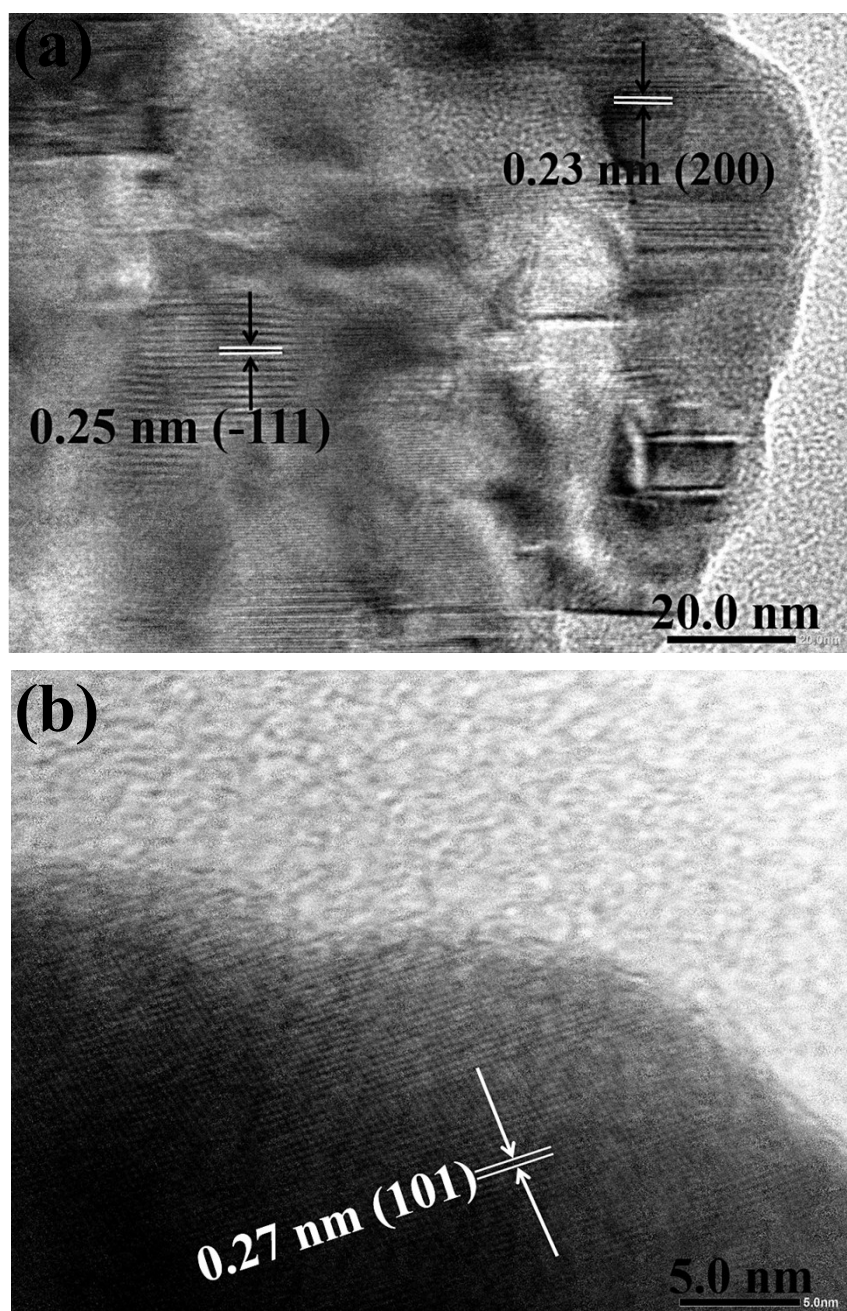


**Fig. S10.** (a) EIS Nyquist plots, the inset shows the equivalent circuit, (b) Bode phase curves and (c) Tafel polarization curves of the symmetric cells based on various CEs, (d) OCVD plots of different CEs films.





**Fig. S11.** TEM of CuO (a) and CuO-2 (b).



**Fig. S12.** HRTEM of CuO-2 (a) and Cu<sub>2</sub>S-2 (b).

**Table S4.** Result comparisons of present performance parameters with other reports of similar counter electrodes.

Counter electrode	QD	$R_s$ ( $\Omega$ )	$J_0$ (mA/cm <sup>2</sup> )	$J_{sc}$ (mA/cm <sup>2</sup> )	$V_{oc}$ (V)	FF	PCE (%)	Reference
<b>Cu<sub>2</sub>S-2</b>	CdS/CdSe	2.134	3.45	21.33	0.54	0.52	5.94	Present work
<b>Cu<sub>2</sub>S/brass</b>	CdS/CdSe	2.511	1.52	16.42	0.57	0.53	4.96	Present work
<b>Cu<sub>2</sub>S</b>	CdS/CdSe	2.542	1.36	20.33	0.53	0.45	4.93	Present work
<b>Cu<sub>2</sub>S</b>	CdS/CdSe	2.93	/	15.71	0.48	0.42	3.16	[1]
<b>RGO/Cu<sub>2</sub>S-2</b>	CdS/CdSe	2.48	/	17.11	0.58	0.48	4.76	[1]
<b>Cu<sub>2</sub>S</b>	CdS/CdSe	/	/	11.69	0.60	0.44	3.18	[2]
<b>Electrodeposited CuS</b>	CdS/CdSe	2.50	0.54	16.05	0.55	0.48	4.32	[3]
<b>Spray pyrolyzed Cu<sub>2</sub>S</b>	CdS/CdSe	/	/	14.30	0.51	0.51	3.75	[4]
<b>CuS/brass</b>	CdS/CdSe	2.97	0.006	17.40	0.38	0.58	3.82	[5]
<b>Cu<sub>2</sub>S(5)on ITO</b>	CdSe	/	/	17.70	0.55	0.49	4.78	[6]
<b>Cu<sub>2</sub>S/carbon</b>	CdS/CdSe	8.23	/	13.69	0.59	0.48	3.87	[7]
<b>Cu<sub>1.8</sub>S</b>	CdS/CdSe	6.11	/	16.07	0.50	0.41	3.30	[8]
<b>CuS</b>	CdS/CdSe	6.53	/	15.08	0.51	0.51	3.95	[8]
<b>Cu<sub>2</sub>S</b>	CdS/CdSe	12.14	/	13.45	0.45	0.60	3.65	[9]
<b>Cu<sub>2</sub>S</b>	CdS/CdSe	26.12	/	13.05	0.51	0.63	4.22	[10]

## Reference

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